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Application/Control No.	Applicant(s)/Patent under Reexamination		
10/634,747	SESSER ET AL.		
Examiner	Art Unit		
Dinh Q. Nguyen	3752		

SEARCHED				
Class Sub		Subclass	Date	Examiner
23	8	204		
	<u> </u>	214.17		
		214.19		
		214.23		
		222.11		
		222.15		
		222.17		
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		233		
		243		
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		246		
	i	47	3-21-05	(A)
UPI	ME	SEARCH	1/04/06	WN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
239	204		
	214.13		
	222.13		
	252		
	247	1/04/06	WN

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
CAST SEARCH ATTACHED PEF 09/8/8, 275			
10/119, 294 UPDATED EAST	3-21-05	M M	
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